

RE-ENTRANT FILTER ANALYSIS YIELDING BROADBAND AND COMPACT DESIGNS

This article presents a more thorough validation of an analysis method of a re-entrant filter and augments the work performed previously on this type of filter. Validation of the analysis was achieved by comparing results with the High Frequency Structure Simulator (HFSSTM) and measurements of a prototype unit. The analysis model was improved from previous work! by including frequency-dependent microstrip-to-slot line coupling effects, slot line impedance computations and a better capacitive gap model. The analysis method yielded good agreement with measured data and accurate HFSS simulations.

The work presented in this article for the re-entrant filter is a more thorough validation of re-entrant filter analysis results with further enhancements to the trans-

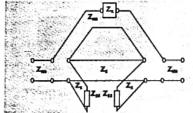
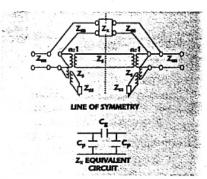


Fig. 2 The original T-line analysis circuit model.

mission line (T-line) model equations. This novel filter topology and an analysis method were first presented in in 1995. A re-entrant filter lavout is shown in Figure 1. The analysis circuit model used originally1 is shown in Figure 2. The circuit used in the analysis is a planar combination of microstrip and slot line transmission lines with capacitive coupling between the microstrip lines, as shown in Fig-ure 3. This combination produces a broadband, highpass, elliptic/ pseudo-elliptic function response in a compact geometry. The beauty of incorporating the re-entrant filter geometry in designs is that it lends itself not just to a highpass response, but also to lowpass and bandpass re-



▲ Fig. 3 The enhanced T-line circuit.

[Continued on page 22]

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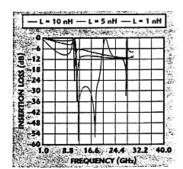
sponses as shown in *Figures 4* and 5, respectively. A lowpass configuration is achieved by replacing the capacitive element with an inductive element and by selecting the proper microstrip and slot line lengths. The response of the lowpass configuration using a 5 nH inductance could be used alternatively as a-band-stop response. A bandpass response also can be achieved by the proper selection of microstrip and slot line lengths.

However, the possibility of realizing a lowpass re-entrant filter appears limited by at least two factors: the availability of inductors in the range of those shown at microwave frequencies, and the short rejection band seen with both the lowpass and bandpass responses. As is the case with distributed element filters, the attenuation does not increase monotonically. By nature, the re-entrant filter is a highpass filter since the cou-

pling between the microstrip and the slot line tends to go to zero as the frequency approaches DC. The selectivity of the filter response can be varied by judicious selection of the capacitive gap and the stub lengths.

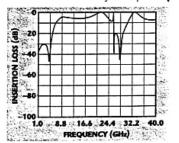
The circuit function can be described simply. When current is applied to the microstrip an incident wave flows toward the microstrip-toslot line transition. The slot line causes a current discontinuity on the ground plane, which causes an electric field to be coupled into the slot line circuit. In the slot line the signal is divided into two traveling waves: a forward and a reverse wave moving away from the junction along the slot line. The reverse wave travels along the slot line short- or open-circuited stub only to be reflected back to interact with the junction once more. The forwardwave signal propagates down the slot line toward the second microstrip-toslot line transition. This forward signal forms the re-entrant path, which gives the geometry its name.

The re-entrant filter analysis is based on even-/odd-mode analysis⁴ and the equations were implemented into MATHCAD™ The MATHCAD



▲ Fig. 4 The re-entrant filter response in a lowpass configuration.

Fig. 5 The re-entrant bandpass filter response.



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program used to perform the analysis for the material presented here is much more sophisticated than the program used previously. I and contains frequency-dependent enhancements that were not included in the original work. This article explains these enhancements and why they are needed. MATHCAD was used to observe the effects of Z_{ss} values on the filter transfer function, which are shown in *Figure 6*. The stub and ca-

pacitive gap produce the characteristic elliptic function response.

The previous work performed on the re-entrant filter had some limitations. For example, in the value of \mathbb{Z}_x of the analysis circuit the capacitive gap was simulated as a simple lumped element in the microstrip line. This method was used to show the effects of a capacitive coupled microstrip line path on the filter response. As a result, the original analy-

sis¹ lacked some subtle effects, which would become more noticeable at higher frequencies or at very low frequencies. This original analysis used the Schuppert model,⁵ which assumes perfect coupling for the microstrip-to-slot line junction and produced good results for most cases. However, at lower frequencies the model did not show the coupling degradation that should occur.

The work described in this article has attempted to include some of these effects. In order to obtain higher fidelity from the T-line analysis for a wider spectrum of frequencies, the enhancements to the analysis involve a less-than-perfect microstrip-to-slot line coupling with frequency,6.7 slot line impedance and wavelength cal-culation from physical dimensions, 6-9 microstrip impedance and effective dielectric constant,10 and a microstrip gap model.⁶ Other effects, such as those of the slot line bends (mitered or unmitered) and mutual coupling between the microstrip and slot lines, would be difficult to simulate. The effects of imperfect coupling were included by adding an n:1 turns ratio transformer to the Schuppert5 model in the slot line circuit and slot line stub sections of the model, with the value of n being frequency dependent. This method is a combination of the Schuppert and Knorr transitions4.5 with Cohn's slot voltage definition.7 The Schuppert model5 is a special case when the value of n is equal to 1. Otherwise, the frequency dependency of n is introduced through Equation 2 using Cohn's definition.6.7 To obtain the coupling value n, the slot line is assumed to be in

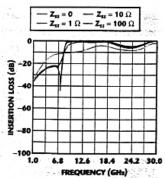
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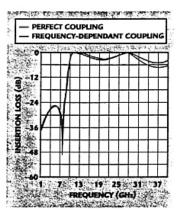




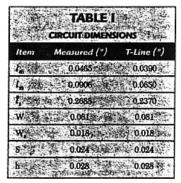
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📤 Fig. 7 A filter response comparison between perfect and imperfect coupling.



a cylindrical coordinate system (x, r, where x is in the direction of propagation for the slot line. The variable r is the radial direction that will be replaced by h, the ground plane spac-

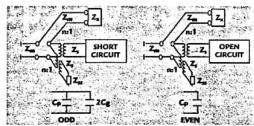


Fig. 8 Odd- and even-mode equivalent circuits

ing, in the analysis. A field is assumed to exist in the slot line, which can be represented by a magnetic line current source. This magnetic line current would have three far-field components, two magnetic fields (Hx and H_{\bullet}) and one electric field (E_{ϕ}) . The En field decays with distance r and provides a voltage relationship between the slot line voltage (V_s) and the microstrip line voltage (V_m) . The transformer turns ratio n is defined as V_m/V_s. The effects of frequency-dependent (less than perfect) coupling compared to the n = 1 case are shown in Figure 7. As expected, the coupling between the lines at the higher frequencies decreases as the fields become more tightly bound to the slot line.

The focus of the work presented here has been directed toward validating the T-line analysis for the reentrant filter. The analysis validation was performed against a prototype circuit and a finite element analysis tool (the HFSS). The physical dimensions of the prototype unit were measured using a measurement microscope and are listed in Table 1.

The analysis model reactive impedance Z_x has been replaced with a more elaborate ca-

pacitive gap model than the original. The capacitive π network, shown in Figure 8,6 is used to model the microstrip gap. Most of the published data for this type of microstrip discontinuity are for high dielectric constants ($\varepsilon_r \ge 9$), so slight adjustments had to be made to the capacitive values. The capacitive values for C_p and C_g are computed in the program given the physical dimensions of the gap.

The closed-form equations used for calculating the slot line impedance and wavelength were obtained for $2 \le \varepsilon_r \le 9.6$ and $9.7 \le \varepsilon_r \le 20.6.8$ The results from these equations were compared to results obtained using Cohn's method.7 Cohn used a fictitious waveguide constructed from perfect electrical conducting (PEC) and perfect magnetic conducting walls. Then, the transverse resonance method with a transverse electric (TE) and transverse magnetic (TM) modal expansion was applied to solve for both the impedance and the slot

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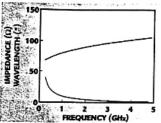
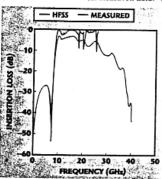


Fig. 9 Cohn's impedance and wavelength vs. frequency.

Fig. 10 HFSS simulation vs. measured data. 🔻



line wavelength. The method was implemented into a MATHCAD program, which computed slot line impedance and wavelength. The equations^{6.8} and the results using Cohn's approach agreed closely. The slot line impedance frequency dependence was as expected from a nonpure TEM transmission line, as shown in Figure 9. The cutoff wavelength effect caused by the fictitiously created waveguide can be observed. If a different set of values is used for the analysis, this cutoff effect will change. The analysis program also was fitted with equations to compute microstrip impedance and effective dielectric constant. The closed-form expressions used for this calculation were obtained from Collin.10

HFSS was used to analyze the prototype circuit based on the physical dimensions resulting from its dielectric constant ($\varepsilon_r = 2.3$). The HFSS results agreed closely with the measured data and are shown in Figure The prototype was measured initially with SMA connectors on both microstrip ends using a model HP

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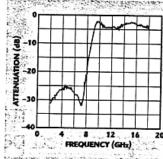
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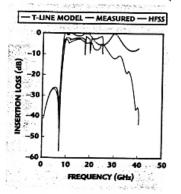
8510C vector network analyzer, and the data are shown in Figure 11. The HFSS data show some glitches in the response. These glitches are an HFSS-induced artifact due to the PEC enclosure, which was applied to truncate the problem space in HFSS. Although radiation boundary conditions can be used, the size of the analysis would become prohibitive.

As shown in Figure 12, the T-line analysis results also agreed closely with the measured prototype data. The T-line analysis shows that a much wider response could be expected from the filter than was observed from the prototype. Therefore, the SMA connectors were replaced by much higher frequency K connectors. As suspected, the circuit was band limited by the SMA connectors. A significant improvement in bandwidth was achieved with the K connectors. No attempt was made to match the connectors properly to the



▲ Fig. 11 The prototype re-entrant

Fig. 12 T-line analysis vs. measured and HFSS data.



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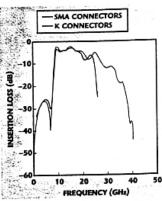
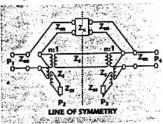


Fig. 13 A measured data comparison using SMA and K connectors.

▼ Fig. 14 Re-entrant filter designations.



re-entrant circuit. The measured data comparison is shown in Figure 13.

THEORETICAL ANALYSIS

The analysis of the prototype circuit is based on an even-/odd-mode analysis4 of the T-line circuit, as shown in Figure 14. The variables shown in the circuit are defined as

= microstrip line impedance

slot line impedance

slot line stub impedance

= even-mode impedance of the microstrip gap

= odd-mode impedance of the

microstrip gap

even-mode impedance of

the microstrip circuit

odd-mode impedance of the $Z_{mmo} =$

microstrip circuit

even-mode admittance

of the slot line circuit odd-mode admittance

of the slot line circuit

microstrip line length

(one side only)

 $l_{
m s} \ l_{
m ss} \
m h$ total slot line length = slot line stub length

ground plane spacing

microstrip wavelength

 λ_{m} slot line wavelength series capacitive element

shunt capacitive element

slot line propagation constant

= slot line-to-microstrip coupling V_m/V_s

The equivalent circuit for a microstrip-to-slot line junction has been published by several authors.^{2–4,6,7,9} For the purpose of setting up the ABCD matrix equations to analyze the re-entrant circuit, the slot line stub is assumed to be simply a port. The re-entrant filter port definitions are shown. In the general analysis, Zss is assumed to be a variable impedance that terminates the slot line port. However, Z_{ss} takes on a value of 0 in the analysis and the length of the slot line stub is determined by the desired reject frequency. The even and odd sources are connected to the two microstrip ports (ports 1 and 4) with the line of symmetry, as shown previously. The ABCD matrix coefficients used for the T-line analysis and the equations obtained from the evenand odd-mode equivalent circuits are derived using

$$k_c = j \frac{2\pi}{\lambda_0} \sqrt{\left(\frac{\lambda_0}{\lambda_s}\right)^2 - 1}$$
 (1)

$$n = \frac{\pi}{2} \left| k_c h H_1^{(1)} \left(k_c h \right) \right| \qquad (2)$$

even mode:

$$Z_{ge} = \frac{1}{j2\pi f C_p}$$
 (3)

$$Z_{\text{nume}} = Z_{\text{in}} \left(\frac{Z_{\text{ge}} + jZ_{\text{in}} \tan \left(\beta_{\text{in}} l_{\text{in}} \right)}{Z_{\text{in}} + jZ_{\text{ge}} \tan \left(\beta_{\text{in}} l_{\text{in}} \right)} \right) \tag{4}$$

$$Y_{se} = j \frac{1}{n^2 Z_s} \tan \left(\frac{2\pi}{\lambda_s} l_s \right)$$
 (5)

$$\begin{bmatrix} A & B \\ C & D \end{bmatrix}_{\text{EVEN}} = \begin{bmatrix} 1 & Z_{\text{mine}} \\ 0 & 1 \end{bmatrix} \begin{bmatrix} 1 & 0 \\ Y_{\text{sr}} & 1 \end{bmatrix} \begin{bmatrix} n & 0 \\ 0 & \frac{1}{n} \end{bmatrix}$$
$$\begin{bmatrix} \cos(\beta_s J_{\text{ss}}) & jZ_s \sin(\beta_s J_{\text{ss}}) \\ j\frac{1}{Z_s} \sin(\beta_s J_{\text{ss}}) & \cos(\beta_s J_{\text{ss}}) \end{bmatrix}$$
(6)

$$\begin{aligned} \mathbf{A}_{e} &= \mathbf{n} \Big(1 + \mathbf{Z}_{mme} \mathbf{Y}_{se} \Big) \cos \left(\frac{2\pi}{\lambda_{s}} l_{ss} \right) \\ &+ \mathbf{j} \frac{\mathbf{Z}_{mme}}{\mathbf{n} \mathbf{Z}_{s}} \sin \left(\frac{2\pi}{\lambda_{s}} l_{ss} \right) \end{aligned} \tag{7}$$

$$B_{e} = jnZ_{s}\left(1 + Z_{mme}Y_{se}\right)sin\left(\frac{2\pi}{\lambda_{s}}l_{ss}\right) + j\frac{Z_{mme}}{n}cos\left(\frac{2\pi}{\lambda}I_{ss}\right)$$
(8)

$$C_{e} = nY_{se} \cos\left(\frac{2\pi}{\lambda_{s}}l_{ss}\right) + j\frac{nY_{sc}}{Z_{s}}\sin\left(\frac{2\pi}{\lambda_{s}}l_{ss}\right)$$
(9)

$$D_{e} = jnY_{se} Z_{s} sin\left(\frac{2\pi}{\lambda_{s}} I_{ss}\right) + \frac{1}{n} cos\left(\frac{2\pi}{\lambda_{s}} I_{ss}\right)$$

$$(10)$$

$$Z_{go} = \frac{1}{j2\pi f(C_p + 2C_g)}$$
 (11)

$$Z_{mmo} = Z_{m} \left(\frac{Z_{go} + jZ_{m} tan \left(\beta_{m} I_{m} \right)}{Z_{m} + jZ_{go} tan \left(\beta_{m} I_{m} \right)} \right)$$
(12)

$$Y_{so} = \frac{-j}{n^2 Z_s} \cot \left(\frac{2\pi}{\lambda_s} l_s \right)$$
 (13)

$$\begin{bmatrix} A & B \\ C & D \end{bmatrix}_{\text{ODD}} = \begin{bmatrix} 1 & Z_{\text{numo}} \\ 0 & 1 \end{bmatrix} \begin{bmatrix} 1 & 0 \\ Y_{so} & 1 \end{bmatrix} \begin{bmatrix} n & 0 \\ 0 & \frac{1}{n} \end{bmatrix}$$
$$\begin{bmatrix} \cos(\beta J_{ss}) & jZ\sin(\beta J_{ss}) \\ j\frac{1}{Z_{s}}\sin(\beta J_{ss}) & \cos(\beta J_{ss}) \end{bmatrix}$$
(14)

$$A_o = n \left(1 + Z_{mmo} Y_{so}\right) \cos \left(\frac{2\pi}{\lambda_s} l_{ss}\right) + j \frac{Z_{mmo}}{nZ} \sin \left(\frac{2\pi}{\lambda_s} l_{ss}\right)$$
(15)

$$B_{o} = jnZ \left(1 + Z_{mimo} Y_{so}\right) \sin\left(\frac{2\pi}{\lambda_{s}} I_{ss}\right) + \frac{Z_{mimo}}{n} \cos\left(\frac{2\pi}{\lambda_{s}} I_{ss}\right)$$
(16)

$$C_{o} = nY_{so}\cos\left(\frac{2\pi}{\lambda_{s}}l_{ss}\right) + j\frac{nY_{so}}{Z_{s}}\sin\left(\frac{2\pi}{\lambda_{s}}l_{ss}\right)$$
(17)

$$D_{o} = jnY_{so}Z_{s}sin\left(\frac{2\pi}{\lambda_{s}}l_{ss}\right) + \frac{1}{n}cos\left(\frac{2\pi}{\lambda_{s}}l_{ss}\right)$$
(18)

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To obtain the reflection coefficient Γ_e at port P1 with P2 terminated into Z_{ss} , the ABCD matrix definition at P1 is used as

$$\begin{bmatrix} V_1 \\ I_1 \end{bmatrix}_{\text{EVEN}} = \begin{bmatrix} A_e & B_e \\ C_e & D_e \end{bmatrix} \begin{bmatrix} V_2 \\ I_2 \end{bmatrix} \quad (19)$$

At P2, V_2 is defined in terms of the terminating impedance Z_{ss} and the current I_2

$$V_2 \equiv Z_{ss}I_2 \qquad (20)$$

Substituting for V_2 in Equation 19 yields

$$\begin{bmatrix} V_1 \\ I_1 \end{bmatrix}_{\text{EVEN}} = \begin{bmatrix} A_e & B_e \\ C_e & D_e \end{bmatrix} \begin{bmatrix} Z_{ss}I_2 \\ I_2 \end{bmatrix} \quad (21)$$

The equation for the input impedance at P1 is the ratio of V_1 over I_1 .

Thus, from Equation 21,

$$Zin_e = \frac{V_1}{I_1}\Big|_e = \frac{A_e Z_{ss} + B_e}{C_c Z_{ss} + D_e}$$
 (22)

From this input impedance and the characteristic impedance (\mathbf{Z}_0) , the reflection coefficient is given by

$$\Gamma_e = \frac{\operatorname{Zin}_e - Z_0}{\operatorname{Zin}_e + Z_0}$$
(23)

Replacing Z_0 with the characteristic impedance for microstrip Z_m and substituting the ABCD matrix coefficients from the previous equation, the equation Γ_e then becomes

$$\Gamma_{e} = \frac{A_{e}Z_{ss} - D_{e}Z_{m} + B_{e} - C_{e}Z_{ss}Z_{m}}{A_{e}Z_{ss} + D_{e}Z_{m} + B_{e} - C_{e}Z_{ss}Z_{m}}$$
(24)

For the odd-mode case, the equation for Γ_0 is derived similarly as

$$\Gamma_{\rm o} = \frac{A_{\rm o}Z_{ss} - D_{\rm o}Z_{\rm m} + B_{\rm o} - C_{\rm o}Z_{ss}Z_{\rm m}}{A_{\rm o}Z_{ss} + D_{\rm o}Z_{\rm m} + B_{\rm o} - C_{\rm o}Z_{ss}Z_{\rm m}}$$
 (25)

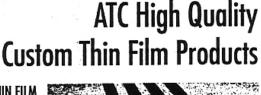
To obtain the signal flow from port 1 to port 4, the odd-/even-mode coefficients are combined to obtain the signal at P4 as designated by Wheeler. The equation for the signal at port 4 relative to an input at port 1 is herein defined as the transmission coefficient S_{21} for the overall circuit and is given by

$$S_{21} = \frac{1}{2} \left(\Gamma_e - \Gamma_o \right) \qquad (26)$$

RESULTS

The results of this analysis are compared to the measurements made on the prototype unit and the HFSS results. The prototype's physical dimensions were used in the HFSS and the T-line analysis. These values are in good agreement with each other. which further demonstrates the validity of the analysis. Furthermore, the results are in good agreement with the measured data. Neither the HFSS simulation nor the T-line analysis model included conductor losses although these certainly could be included with minimal work. The results of the T-line analysis and the HFSS solution also were compared and agree closely.

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CONCLUSION

This article shows that relatively accurate results may be obtained for predicting the re-entrant filter response using a simple analysis method. This analysis method also can be used for designing multi-octave filters with a compact geometry. The analysis method has been shown to yield comparable results to those of a finite element model solution with a significant reduction in com-

putational time. Although the results for the analysis show good agreement, additional refinements of the model would further improve the accuracy. Slight differences exist between the physical data and the T-line data due to the effects unaccounted for in the T-line model. These types of effects were noted by other authors originally^{5,9} and were accounted for by lengthening or shortening the microstrip and slot

line circuits. The improvements include the effects mentioned previously such as slot line bends (mitered or unmitered) for slot lines and parasitic coupling between the microstrip and the slot line. However, obtaining closed-form solutions for these effects is not a trivial task.

ACKNOWLEDGMENT

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